Automotive Qualification Results Summary for ADuM1400W/ADuM1401W/ADuM1402W Die Revision, Assembly Site Transfer, Test Platform Migration, Data Sheet and MSL Rating Change

QUALIFICATION PLAN / STATUS					
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS		
High Temperature Operating Life (HTOL)*	JEDEC JESD22-A108	8x77 1x45	Pass		
Highly Accelerated Stress Test (HAST)*	JEDEC JESD22-A110	9x77	Pass		
Temperature Cycle (TC)*	JEDEC JESD22-A104	9x77	Pass		
Autoclave (AC)*	JEDEC JESD22-A102	9x77	Pass		
High Temperature Storage Life (HTSL)	JEDEC JESD22-A103	9x77	Pass		
Solder Heat Resistance (SHR)*	JEDEC/IPC J-STD-020	3x10	Pass		
Latch-Up	JEDEC JESD78	1x9	Pass ±100mA @ +8.25V		
Electrostatic Discharge Human Body Model	ESDA/JEDEC JS-001	1x18	Pass ±4000V		
Electrostatic Discharge Field-Induced Charged Device Model	JEDEC JESD22-C101	1x18	Pass ±1250V		

^{*} Pre- and post-stress electrical test was performed at room and hot temperatures. These samples were subjected to preconditioning (per J-STD-020 Level 3) prior to the start of the stress test. Level 3 preconditioning consists of the following: Bake: 24 hrs @ 125°C, Unbiased Soak: 192 hrs @ 30°C, 60%RH, Reflow: 3 passes through an oven with a peak temperature of 260°C.

TEST PRODUCT QUALIFICATION REPORT

TITLE:

ADuM1400W/ADuM1401W/ADuM1402W SOIC_W Test Platform Migration from CTS 5040 to Teradyne Microflex

PCN NUMBER:

16_0209

REVISION:

Α

DATE:

November 08, 2016

SUMMARY

The ADuM1400W/ADuM1401W/ADuM1402W are quad-channel digital isolators based on Analog Devices, Inc., *i*Coupler® technology. Combining high speed CMOS and monolithic air core transformer technology, these isolation components provide outstanding performance characteristics superior to alternatives, such as optocoupler devices. This product is being tested on the CTS5040 which is a constrained ADI manufactured tester. The proposed change is to add a new test capability on Microflex which is being manufactured by Teradyne.

There is no change to the form, fit, function, quality or reliability of the transferred parts.

This report documents the result of the evaluations done to qualify the Teradyne Microflex as an additional platform for testing the ADuM1400W/ADuM1401W/ADuM1402W devices.

TEST AND PRODUCT INFORMATION

Devices(Generics):	ADuM1400/ADuM1401/ADuM1402	
Package:	SOIC_W	
Leads:	16	
Parts Affected:	ADUM1400WSRWZ	
	ADUM1400WSRWZ-RL	
	ADUM1400WTRWZ	
	ADUM1400WTRWZ-RL	
	ADUM1401WSRWZ	
	ADUM1401WSRWZ-RL	
	ADUM1401WSRWZ55	
	ADUM1401WSRWZ55-RL	
	ADUM1401WTRWZ	
	ADUM1401WTRWZ-RL	
	ADUM1401WTRWZ55	
	ADUM1401WTRWZ55-RL	
	ADUM1402WSRWZ	
	ADUM1402WSRWZ-RL	
	ADUM1402WSRWZ55	
	ADUM1402WSRWZ55-RL	
	ADUM1402WTRWZ	
	ADUM1402WTRWZ-RL	
Current Platform:	CTS5040 with MT9308_PB_RW handler	
New Platform:	Teradyne Microflex with MT9308_PB_RW handler	

Description and Test Results (Taken from the Test Platform Migration Criteria)

Table 1 & Table 2 provide a description of the qualification tests conducted and corresponding test results for ADuM1400W/ADuM1401W/ADuM1402W. All the units have undergone electrical tests on both the CTS5040 and Teradyne MicroFlex test platforms. Any device that did not meet the electrical qualification requirements, without further analysis and data to prove passing the qualification would be considered failed.

Table 1: Test Product Correlation Criteria

		Testing	CTS5040	MicroFlex	Mean Shift [(platform1 –
Model	Package	Site	Test Lot Size	Test Lot Size	platform2) / SW GB] < 1
ADuM1400WSRWZ	SOIC_W	ADGT	100	100	Reviewed and Passed
ADuM1400WTRWZ	SOIC_W	ADGT	100	100	Reviewed and Passed
ADuM1401WSRWZ	SOIC_W	ADGT	100	100	Reviewed and Passed
ADuM1401WTRWZ	SOIC_W	ADGT	100	100	Reviewed and Passed
ADuM1402WSRWZ	SOIC_W	ADGT	100	100	Reviewed and Passed
ADuM1402WTRWZ	SOIC_W	ADGT	100	100	Reviewed and Passed

Table 2: Test Product Guard banding (GB) Criteria

		Testing	CTS5040	MicroFlex	GB (5.5* Sigma + Delta Means)
Model	Package	Site	Test Lot Size	Test Lot Size	NI_STS_GP GB = or < SW GB
					or Microflex GB
ADuM1400WSRWZ	SOIC_W	ADGT	100	100	Reviewed and Passed
ADuM1400WTRWZ	SOIC_W	ADGT	100	100	Reviewed and Passed
ADuM1401WSRWZ	SOIC_W	ADGT	100	100	Reviewed and Passed
ADuM1401WTRWZ	SOIC_W	ADGT	100	100	Reviewed and Passed
ADuM1402WSRWZ	SOIC_W	ADGT	100	100	Reviewed and Passed
ADuM1402WTRWZ	SOIC_W	ADGT	100	100	Reviewed and Passed

Table 3 shows results of the qualification lots run for the ADuM1400W/ADuM1401W/ADuM1402W. The qualification lots have undergone electrical test on both CTS5040 and Teradyne MicroFlex test platforms. Any deviation on the lot qualification run criteria without further analysis and data to prove a passing qualification would be considered a failed qualification lot run.

Table 3: Test Product Qualification Results

Model	Package	Lot number	Lot Size	Good units passed on both test platforms?	Reject units failed on the same test parameter for both test platforms?
ADuM1400WSRWZ	SOIC_W	AM69292.1	300	Yes	Yes
ADuM1400WSRWZ	SOIC_W	AM89286.1	300	Yes	Yes
ADuM1400WTRWZ	SOIC_W	LS982369.6	300	Yes	Yes
ADuM1400WTRWZ	SOIC_W	LS982369.7	300	Yes	Yes
ADuM1401WSRWZ	SOIC_W	AK15800.19	100	Yes	Yes
ADuM1401WTRWZ	SOIC_W	LS994330.3	300	Yes	Yes
ADuM1401WTRWZ	SOIC_W	LS994330.4	300	Yes	Yes
ADuM1402WSRWZ	SOIC_W	AM89287.1	300	Yes	Yes
ADuM1402WSRWZ	SOIC_W	AM89287.2	300	Yes	Yes
ADuM1402WTRWZ	SOIC_W	AM66480.1	150	Yes	Yes
ADuM1402WTRWZ	SOIC_W	AM66480.2	150	Yes	Yes

Approvals

Technical Review Board (TRB)

Supporting Document

TRB# 10824

TEST

PRODUCT

QUALIFICATION

REPORT

TITLE:

ADuM1400W/ADuM1401W/ADuM1402W SOIC_W High Voltage Test Platform Migration from Harris-Tuvey to MPS at ADGT

PCN NUMBER:

16_0209

REVISION:

Α

DATE: November 8, 2016

SUMMARY

The ADuM1400W/ADuM1401W/ADuM1402W are quad-channel digital isolators based on Analog Devices, Inc., *i*Coupler® technology. Combining high speed CMOS and monolithic air core transformer technology, these isolation components provide outstanding performance characteristics superior to alternatives, such as optocoupler devices. In accordance with UL and VDE standards, these products are high voltage tested using the Harris-Tuvey 9464 test platform, an aging and limited manufacturing test platform. The proposed change is to add new high voltage test capability using the MPS PD test platform manufactured by MPS Mess-& Prüfsysteme GmbH.

This report documents the result of the evaluations done to qualify the MPS PD tester as an additional high voltage test platform for the ADuM1400W/ADuM1401W/ADuM1402W.

Test product qualification was performed according to Analog Devices Specifications (TST00094/TST00095 – Test Platform Migration Specification).

TEST AND PRODUCT INFORMATION

Device(Generic):	ADuM1400/ADuM1401/ADuM1402			
Package:	SOIC_W			
Leads:	16			
	ADUM1400WSRWZ	ADUM1402WSRWZ		
	ADUM1400WSRWZ-RL	ADUM1402WSRWZ-RL		
	ADUM1400WTRWZ	ADUM1402WSRWZ55		
	ADUM1400WTRWZ-RL	ADUM1402WSRWZ55-RL		
		ADUM1402WTRWZ		
	ADUM1401WSRWZ	ADUM1402WTRWZ-RL		
Parts Affected:	ADUM1401WSRWZ-RL			
	ADUM1401WSRWZ55			
	ADUM1401WSRWZ55-RL			
	ADUM1401WTRWZ			
	ADUM1401WTRWZ-RL			
	ADUM1401WTRWZ55			
	ADUM1401WTRWZ55-RL			
Current Platform:	Harris-Tuvey with Atrium 5050FHV handler			
New Platform:	MPS with Atrium VMAX handler			

Description and Test Results

The high voltage test platform is required to proof test the insulation performance of our products to the regulatory agency standards. The tests conducted on the high voltage test platform are:

Dielectric Insulation Test

In accordance with **UL 1577**, each ADuM1400W/ADuM1401W/ADuM1402W is proof tested by applying an insulation test voltage \geq 3000 Vrms for 1 sec (current leakage detection limit = 5 μ A).

Partial Discharge Test

In accordance with **DIN V VDE V 0884-10** (VDE V 0884-10):2006-12, each ADuM1400W/ADuM1401W/ADuM1402W is proof tested by applying an insulation test voltage ≥ 1050 V peak for 1 sec (partial discharge detection limit = 5 pC).

The Harris-Tuvey high voltage test platform does not provide data logs for units tested; only a pass or fail result is provided. The MPS test platform will provide data logs for leakage current and partial discharge measurements that will be recorded and maintained over time.

The **ADUM1400W**, **ADUM1401W**, **and ADUM1402W** use the same package, coil and isolation process. The four lots listed below, along with additional test results from multiple products using the 16-lead SOIC_W package, were used to qualify the three generics on the MPS test platform.

The results of the qualification lots run for the ADuM140x family are shown in Table 1. The qualification lots have undergone high voltage testing on both Harris-Tuvey and MPS test platforms. Any deviation on the lot qualification run criteria without further analysis and data to prove a passing qualification would be considered a failed qualification lot run.

All units that passed on the Harris-Tuvey platform also passed on the MPS platform and all units rejected by the Harris-Tuvey platform were also rejected by the MPS test platform thereby demonstrating correlation of both good and bad units between platforms.

Table 1: Test Product Qualification Lots

Generic	Package	Lot number	Lot Size	Good units passed on both test platforms?	Reject units failed on the same test parameter for both test platforms?
ADUM1400	SOIC_W	AN41532.4	100	Yes	Yes
ADUM1400	SOIC_W	SA71812.2	100	Yes	Yes
ADUM1401	SOIC_W	AN41834.3	100	Yes	Yes
ADUM1401	SOIC_W	SA71809.2	100	Yes	Yes
ADUM1401	SOIC_W	SA71810.2	100	Yes	Yes
ADUM1402	SOIC_W	AN41849.3	100	Yes	Yes

Approvals

Product Line Manager Test Development Manager Test Product Manager Quality Manager

Supporting Document

Technical Review Board: TRB #11654 - ADuM1400/01/02 MPS Migration

Additional Information

Homepage: http://www.analog.com/en/index.html

Datasheet: http://www.analog.com/media/en/technical-documentation/data-

sheets/ADuM1400 1401 1402.pdf

Material Set Change:

Package Material Set		Carsem	ASE Chungli
	Die Attach	Ablestik 84-1LMISR4	Hitachi EN4900GC
SOIC_W	Mold Compound	Sumitomo 6600H	Sumitomo G700LY
	Wire	1.3 mil Gold Wire	1.3mil Gold Wire